Search Notes

Application/Control No.	Applicant(s)/Patent ur Reexamination	nder
10/069,246	OKUMURA, SEIJI	
Examiner	Art Unit	
Dehert M. Mileen	2616	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
370/394, 235, & 231 (Text)	3/16/2006	RWW		
714/18, 748, 749, & 750 (Text)	3/16/2006	RWW		
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